

WAVE CHECK

WAVELENGTH METER - Preliminary Datasheet



WaveCheck is a low-cost, compact device for wavelength measurement of pulsed and cw laser sources from 450 nm to 1000 nm. It is based on an unique non-dispersive measuring principle that requires no further adjustment.

WaveCheck is ideally suited for monitoring the wavelength of tunable lasers and the stability of laser diodes. Wavelengths are shown directly on a bright display with a resolution of 0.1 nm to an accuracy of ± 0.5 nm (± 1.0 nm pulsed).

WaveCheck can be set to fully automatic operation to provide maximum ease of use and optimum parameter setting. On the other hand, all operation parameters including measurement averaging, background offset correction and single pulse sample and hold are menu selectable and can be set to fixed values.

WaveCheck's detector head incorporates an electronically controlled beam shutter for signal offset measurement and a variable neutral density attenuator for adjustment of optimum light intensity. The wavelength sensor is temperature stabilized to guarantee maximum accuracy.

Suitable for cw- and pulsed systems

Ease of use

Compact construction

Adjustment-free optical design and angle insensitive beam input

Fully automatic triggering in pulsed operation

Ultrafast Pulse Diagnostics

Spectral Analysis

Acoustooptics

Pulse Management

Wavelength Conversion

Your Partner in Ultrafast

WAVE CHECK

WaveCheck comes standard with an USB interface for data transfer to a PC computer.
For non-pulsed applications an economical cw only version is available.

SPECIFICATIONS

	CW		Pulsed
	Repetition rates > 5 kHz		Single shot to repetition rates < 5 kHz
Wavelength range		450 ... 1000 nm	
Resolution		0,1 nm	
Accuracy	± 0,5 nm		± 1,0 nm
Sensitivity	20 μ W	(@ 632.8 nm)	10 μ J
Dynamic range	1000 : 1		200 : 1
Damage threshold	75 W / cm ²	with variable attenuator	10 mJ / cm ²
Warm-up time		15 minutes	
Interface		USB	
Input aperture diameter		4 mm	
Power supply		100...240 V, 47 ... 63 Hz	

OPTIONS

High resolution (0,01 nm in cw mode at absolute accuracy of ± 0,5 nm)